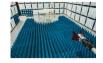


PCTEST KOREA CO., LTD.

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MEASUREMENT REPORT LTE

Applicant Name:

Samsung Electronics Co., Ltd. 129, Samsung-ro, Yeongtong-gu, Suwon-si Gyeonggi-do, 16677, Korea **Date of Testing:**

07/19/2021 - 08/18/2021

Test Site/Location:

PCTEST KOREA Lab. Yongin-si, Gyeonggi-

do, Korea

Test Report Serial No.: 8K21071202-02-R2.A3L

FCC ID: A3LRF4437D-25D

APPLICANT: Samsung Electronics Co., Ltd.

Application Type: Certification

Model: RF4437d-25D

EUT Type: RRU(RF4437d)

FCC Classification: PCS Licensed Transmitter

FCC Rule Part(s): 24 & 27

Test Procedure(s): ANSI C63.26-2015, KDB 971168 D01 v03r01, KDB 662911 D01 v02r01

This revised Test Report (S/N: 8K21071202-02-R2.A3L) supersedes and replaces the previously issued test report (S/N: 8K21071202-02-R1.A3L) on the same subject device for the same type of testing as indicated. Please discard or destroy the previously issued test report(s) and dispose of it accordingly.

This equipment has been shown to be capable of compliance with the applicable technical standards as indicated in the measurement report and was tested in accordance with the measurement procedures specified in §2.947. Test results reported herein relate only to the item(s) tested.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

Prepared by Ian.Kim Test Engineer

Reviewed by Charles.Shin Technical Manager

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MEASUREMENT REPORT



Emission

		FCC Part 24E & 27					
Total Bandwidth	Band	FCC Rule	Tx Frequency	Total	Power		
(MHz)	Danu	Part	(MHz)	MaxPower	Maxi		

Bandwidth (MHz) Band Part Part (MHz) MaxPer (W 41.3 5 LTE Band 2 24E 1930.0 - 35.4 1990.0 35.4 35.4 35.4	/) (dBm) 21 46.15 48 45.50 81 45.54	Designator 4M48G7D 4M47W7D	Modulation QPSK 16QAM
5 LTE Band 2 24E 1930.0 - 35.4 1990.0 35.4 35.3 35.3	48 45.50 81 45.54	4M47W7D	
5 LTE Band 2 24E 1930.0 - 35.4 1990.0 35.4 35.3 35.3	48 45.50 81 45.54	4M47W7D	
5 LTE Band 2 24E 1990.0 35.0 35.0 35.0	81 45.54		
35.4 35.4		4M48W7D	64QAM
35.	56 45.51	4M48W7D	256QAM
		8M97G7D	QPSK
1930.0 — 35.		8M97W7D	16QAM
10 LTE Band 2 24E 1930.0 - 35.		8M98W7D	64QAM
35.		8M96W7D	256QAM
36.		9M44G7D	QPSK
4020.0		9M43W7D	16QAM
(5+5) LTE Band 2 24E 1930.0 - 36. 37.		9M45W7D	64QAM
36.		9M45W7D	256QAM
37.		13M4G7D	QPSK
4020.0		13M4W7D	16QAM
15 LTE Band 2 24E 1930.0 - 36.1 1990.0 37.		13M4W7D	64QAM
37.		13M4W7D	256QAM
37.		14M4G7D	QPSK
		14M4W7D	16QAM
		14M4W7D	64QAM
36.		14M4W7D	256QAM
34.		17M9G7D	QPSK
20 LTE Band 2 24E 1930.0 - 34.		17M9W7D	16QAM
1990.0		17M9W7D	64QAM
35.		17M9W7D	256QAM
35.		23M7G7D	QPSK
25 LTE Band 2 24E 1930.0 - 35.		23M7W7D	16QAM
(5+20) 1990.0 35.3		23M7W7D	64QAM
34.		23M7W7D	256QAM
36.3		28M3G7D	QPSK
30 LTE Band 2 24E 1930.0 - 35.		28M3W7D	16QAM
(10+20) 1990.0 35.		28M3W7D	64QAM
35.		28M3W7D	256QAM
34.		28M6G7D	QPSK
30 LTE Band 2 24E 1930.0 - 35.		28M5W7D	16QAM
(5+5+20) 1990.0 35.3		28M6W7D	64QAM
35.3	32 45.48	28M6W7D	256QAM
47.5		4M48G7D	QPSK
5 LTE Band 66 27 2110.0 - 47.1	64 46.78	4M48W7D	16QAM
2180.0 47.5	53 46.77	4M49W7D	64QAM
47.:	32 46.75	4M48W7D	256QAM
47.	42 46.76	8M97G7D	QPSK
2440.0		8M98W7D	16QAM
10 LTE Band 66 27 2110.0 - 47.		8M99W7D	64QAM
48.		8M97W7D	256QAM
45.		9M44G7D	QPSK
10 2110.0 — 459		9M43W7D	16QAM
I I I E Band 66 I 2/	03 46.63	9M45W7D	64QAM
(5+5) LTE Band 00 27 2180.0 46.0		9M46W7D	256QAM
(5+5) 2180.0 46.1	9Z I 46.6Z		
(5+5) 2160.0 46.1			
(5+5) 2100.0 46.1 45.1 2110.0 48.1	53 46.77	13M4G7D	QPSK
(5+5) 2160.0 46.1	53 46.77 42 46.85		

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<u> </u>				45.50	46.58	14M4G7D	QPSK
15			2110.0 –	45.60	46.59	14M4W7D	16QAM
(5+5+5)	LTE Band 66	27	2180.0	45.71	46.60	14M4W7D	64QAM
(= /				45.39	46.57	14M4W7D	256QAM
				46.77	46.70	17M9G7D	QPSK
			2110.0 –	47.21	46.74	17M9W7D	16QAM
20	LTE Band 66	27	2180.0	46.77	46.70	17M9W7D	64QAM
				47.21	46.74	17M9W7D	256QAM
				47.75	46.79	19M4G7D	QPSK
20	1.TE D 1.00	07	2110.0 –	47.64	46.78	19M4W7D	16QAM
(5+5+5+5)	LTE Band 66	27	2180.0	48.08	46.82	19M4W7D	64QAM
, ,				47.75	46.79	19M4W7D	256QAM
				45.29	46.56	23M7G7D	QPSK
25	LTE David 60	07	2110.0 -	44.98	46.53	23M7W7D	16QAM
(5+20)	LTE Band 66	27	2180.0	45.39	46.57	23M7W7D	64QAM
, ,				44.98	46.53	23M7W7D	256QAM
				45.39	46.57	28M6G7D	QPSK
30	LTE Band 66	27	2110.0 – 2180.0	45.39	46.57	28M6W7D	16QAM
(5+5+20)				45.50	46.58	28M6W7D	64QAM
				45.50	46.58	28M7W7D	256QAM
				46.77	46.70	33M5G7D	QPSK
35	LTE Band 66	27	2110.0 -	46.77	46.70	33M5W7D	16QAM
(5+5+5+20)	LTE Ballu 00	21	2180.0	46.34	46.66	33M5W7D	64QAM
				46.45	46.67	33M6W7D	256QAM
				45.08	46.54	37M9G7D	QPSK
40	LTE Band 66	27	2110.0 -	45.29	46.56	38M0W7D	16QAM
(20+20)	LIL Dand 00	21	2180.0	45.71	46.60	37M9W7D	64QAM
				45.29	46.56	37M9W7D	256QAM
				45.50	46.58	38M5G7D	QPSK
40	LTE Band 66	27	2110.0 –	45.39	46.57	38M5W7D	16QAM
(5+15+20)	LIL Dana 00	۷.	2180.0	45.19	46.55	38M5W7D	64QAM
				44.98	46.53	38M5W7D	256QAM
				44.98	46.53	38M6G7D	QPSK
40	LTE Band 66	27	2110.0 –	46.03	46.63	38M7W7D	16QAM
(5+5+10+20)	LIL Dana 00	۷.	2180.0	45.50	46.58	38M6W7D	64QAM
				45.19	46.55	38M6W7D	256QAM

EUT Overview

Notes:

Total Power shown in the table above are the full conducted average output power that will appear on the Grant of Authorization.

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1.0 INTRODUCTION

1.1 Scope

Measurement and determination of electromagnetic emissions (EMC) of radio frequency devices including intentional and/or unintentional radiators for compliance with the technical rules and regulations of the Federal Communications Commission and the Innovation, Science and Economic Development Canada.

1.2 PCTEST KOREA Test Location

These measurement tests were conducted at the PCTEST KOREA CO., LTD. facility located at (#1407) 13, Heungdeok 1-ro, Giheung-gu, Yongin-si, Gyeonggi-do 16954, Korea.

1.3 Test Facility / Accreditations

Measurements were performed at PCTEST KOREA Lab located in Yongin-si, Gyeonggi, Korea.

- PCTEST KOREA is an ISO 17025:2005 accredited test facility under the National Institute of Standards and Technology (NIST) with Certificate number 600143-0 for Specific Absorption Rate (SAR), where applicable, and Electromagnetic Compatibility (EMC) testing for IC and Innovation, Science, and Economic Development Canada rules.
- PCTEST KOREA facility is accredited, designated and recognized in accordance with the provision of Radio Wave Act and International Standard ISO/IEC 17025:2017 under the National Radio Research Agency.
 - Designation Number / CABID: KR0169
 - Test Firm Registration Number of FCC: 417945
 - Test Firm Registration Number of IC: 26168

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2.0 PRODUCT INFORMATION

2.1 Equipment Description

The Equipment Under Test (EUT) is the **Samsung RRU(RF4437d) FCC ID: A3LRRF4437D-25D**. The test data contained in this report pertains only to the emissions due to the EUT's licensed transmitters that perate under the provisions of Part 24 and 27.

This device supports the following conditional features:

EUT Type:	RRU(RF443	RRU(RF4437d)						
Model Name:	RF4437d-25	RF4437d-25D						
Test Device Serial No.:	S617628270)						
Device Capabilities:	FD-LTE							
O	Band	Tx (Downlink)	Rx (Uplink)					
Operating Band/Frequency Range:	B2:	1930 MHz to 1990 MHz	1850 MHz to 1910 MHz					
- tanger	B66:	2110 MHz to 2180 MHz	1710 MHz to 1780 MHz					
Supported Number of Carriers:		Max. 3 carriers in band 2 Max. 4 carrier in band 66						
Supported Modulation:	LTE: QPSK 256QAM(E-	(E-TM 1.1), 16QAM(E-TM 3.2), 6 TM 3.1a)	64QAM(E-TM 3.1),					
Supported Channel Bandwidth:	5MHz, 10MI	Hz, 15MHz, and 20MHz						
Number of Antenna ports	4							
Supported Configurations:	Single carrie	er, Multi-carrier, Multi-band opera	ation					
Input Voltage:	110 VAC							
Antenna:	☐ Internal a	antenna External antenna						
Antenna Peak Gain:	Max. 12.5 d	Bi (11.5 dBi ± 1dB)						

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2.2 Test Configuration

The setup is as follows:

- a) The EUT ("RRU(RF4437d)") and a Data Unit (DU) are each powered by -48V DC power supply.
- b) The DU is connected to a test laptop via an ethernet cable acting as backhaul.
- c) DU connects to the EUT through a fiber optic cable.
- d) An RF cable connects the signal analyzer and the EUT Ports for respective measurement.

The EUT was tested per the guidance of ANSI C63.26-2015 and KDB 971168 D01 v03r01. See Section 7.0 of this test report for a description of the radiated and antenna port conducted emissions tests..

The following information is about configurations of carrier frequency and output power per port declared by the manufacturer.

			Carrier Configuration									
Configuration	Operation	Channel	1st Ca	arrier	2 nd C	arrier	3rd C	arrier	4th Ca	arrier		
			Fre.(MHz)	BW(MHz)	Fre.(MHz)	BW(MHz)	Fre.(MHz)	BW(MHz)	Fre.(MHz)	BW(MHz)		
		Lowest	1932.5									
B2_5M_1C	Single	Middle	1960.0	5								
		Highest	1987.5									
		Lowest	1935.0									
B2_10M_1C	Single	Middle	1960.0	10								
		Highest	1985.0		N/A							
		Lowest	1937.5				IN,	/A				
B2_15M_1C	Single	Middle	1960.0	15								
		Highest	1982.5									
		Lowest	1940.0									
B2_20M_1C	Single	Middle	1960.0	20								
		Highest	1980.0									
	Contiguous	Lowest	1932.5	5	1937.5	5						
B2 5M+5M 2C		Middle	1957.5	5	1962.5	5						
BZ_SIVI+SIVI_ZO		Highest	1982.5	5	1987.5	5						
	Non-contiguous		1932.5	5	1987.5	5						
		Lowest	1932.5	5	1945.0	20						
B2_5M+20M	Contiguous	Middle	1950.0	5	1962.5	20		N/A				
_2C		Highest	1967.5	5	1980.0	20		I N				
	Non-cont	tiguous	1932.5	5	1980.0	20						
		Lowest	1935.0	10	1950.0	20						
B2_10M+20M	Contiguous	Middle	1950.0	10	1965.0	20						
_2C		Highest	1965.0	10	1980.0	20						
	Non-cont	tiguous	1935.0	10	1980.0	20						
		Lowest	1932.5	5	1937.5	5	1942.5	5				
B2_5M+5M+5M	Contiguous	Middle	1955.0	5	1960.0	5	1965.0	5				
_3C		Highest	1977.5	5	1982.5	5	1987.5	5				
	Non-conf	tiguous	1932.5	5	1960.0	5	1987.5	5	N,	/Δ		
		Lowest	1932.5	5	1937.5	5	1950.0	20	IN,			
B2_5M+5M	Contiguous	Middle	1947.5	5	1952.5	5	1965.0	20]			
+20M_3C		Highest	1962.5	5	1967.5	5	1980.0	20				
	Non-conf	tiguous	1932.5	5	1960.0	5	1980.0	20				

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			Carrier Configuration							
Configuration Operation		Channel	1 st Carrier 2 nd Carrier			3 rd Carrier 4 th Carrier			arrier	
			Fre.(MHz)	BW(MHz)	Fre.(MHz)	BW(MHz)	Fre.(MHz)	BW(MHz)	Fre.(MHz)	BW(MHz)
		Lowest	2112.5							
B66_5M_1C	Single	Middle	2145.0	5						
		Highest	2177.5							
		Lowest	2115.0							
B66_10M_1C	Single	Middle	2145.0	10						
		Highest	2175.0					(A		
		Lowest	2117.5				N	A		
B66_15M_1C	Single	Middle	2145.0	15						
		Highest	2172.5							
		Lowest	2120.0							
B66_20M_1C	Single	Middle	2145.0	20						
		Highest	2170.0							
		Lowest	2112.5	5	2117.5	5				
B66_5M+5M	Contiguous	Middle	2142.5	5	2147.5	5				
_2C		Highest	2172.5	5	2177.5	5				
	Non-con	tiguous	2112.5	5	2177.5	5				
		Lowest	2112.5	5	2125.0	20				
B66_5M+20M	Contiguous	Middle	2135.0	5	2147.5	20				
_2C		Highest	2157.5	5	2170.0	20		N.	/A	
	Non-con	tiguous	2112.5	5	2170.0	20				
		Lowest	2120.0	20	2140.0	20				
B66_20M+20M	Contiguous	Middle	2135.0	20	2155.0	20				
_2C		Highest	2150.0	20	2170.0	20				
	Non-con	tiguous	2120.0	20	2170.0	20				
		Lowest	2112.5	5	2117.5	5	2122.5	5		
B66_5M+5M	Contiguous	Middle	2140.0	5	2145.0	5	2150.0	5		
+5M_3C	-	Highest	2167.5	5	2172.5	5	2177.5	5		
	Non-con	tiguous	2112.5	5	2145.0	5	2177.5	5		
		Lowest	2112.5	5	2117.5	5	2130.0	20		
B66_5M+5M	Contiguous	Middle	2132.5	5	2137.5	5	2150.0	20		
+20M_3C		Highest	2152.5	5	2157.5	5	2170.0	20	N.	/A
	Non-con	tiguous	2112.5	5	2145.0	5	2170.0	20		
		Lowest	2112.5	5	2122.5	15	2140.0	20		
B66_5M+15M	Contiguous	Middle	2127.5	5	2137.5	15	2155.0	20		
+20M_3C	_	Highest	2142.5	5	2152.5	15	2170.0	20		
	Non-con	tiguous	2112.5	5	2145.0	15	2170.0	20		
		Lowest	2112.5	5	2117.5	5	2122.5	5	2127.5	5
B66_5M+5M	Contiguous	Middle	2137.5	5	2142.5	5	2147.5	5	2152.5	5
+5M+5M_4C	J	Highest	2162.5	5	2167.5	5	2172.5	5	2177.5	5
	Non-con	_	2112.5	5	2137.5	5	2152.5	5	2177.5	5
		Lowest	2112.5	5	2117.5	5	2122.5	5	2135.0	20
B66_5M+5M	Contiguous	Middle	2130.0	5	2135.0	5	2140.0	5	2152.5	20
+5M+20M_4C	J	Highest	2147.5	5	2152.5	5	2157.5	5	2170.0	20
	Non-con		2112.5	5	2130.0	5	2145.0	5	2170.0	20
		Lowest	2112.5	5	2117.5	5	2125.0	10	2140.0	20
B66_5M+5M	Contiguous	Middle	2127.5	5	2132.5	5	2140.0	10	2155.0	20
+10M+20M_4C	J	Highest	2142.5	5	2147.5	5	2155.0	10	2170.0	20
	Non-con		2112.5	5	2127.5	5	2145.0	10	2170.0	20

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					Carrier Configuration					
Configuration	Operation	Channel	1st Ca	arrier	2 nd C	arrier	3 rd Carrier		4 th Carrier	
			Fre.(MHz)	BW(MHz)	Fre.(MHz)	BW(MHz)	Fre.(MHz)	BW(MHz)	Fre.(MHz)	BW(MHz)
Multi Band_	Continuous	B2_ Lowest	1932.5	5						
B2_5M_1C_Low+ B66_5M_1C_High	Contiguous	B66_ Highest	2177.5	5						
Multi Band_	0	B2_ Highest	1987.5	5	N/A					
B2_5M_1C_High+ B66_5M_1C_Low	Contiguous	B66_ Lowest	2112.5	5						
Multi Band_B2_5M+5M	0 "	B2_ Lowest	1932.5	5	1937.5	5	1942.5	5		
+5M_3C_Low + B66_5M+5M+5M_ 3C_High	Contiguous	B66_ Highest	2167.5	5	2172.5	5	2177.5	5		
Multi Band_B2_5M+5M	0 "	B2_ Highest	1977.5	5	1982.5	5	1987.5	5		
+5M_3C_High + B66_5M+5M+5M_ 3C_Low	Contiguous	B66_ Lowest	2112.5	5	2117.5	5	2122.5	5	N.	'A
Multi Band_B2_5M+5M +5M_3C - Non- contiguous +	B2_Non-co	ontiguous	1932.5	5	1960.0 5 1987.5 5 2145.0 5 2177.5 5					
contiguous + B66_5M+5M+5M+ 5M_3C - Non- contiguous	B66_Non-c	ontiguous	2112.5	5						

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2.3 EMI Suppression Device(s)/Modifications

No EMI suppression device(s) were added and no modifications were made during testing.

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3.0 DESCRIPTION OF TESTS

3.1 Measurement Procedure

The measurement procedures described in the document titled "American National Standard for Compliance Testing of Transmitter Used in Licensed Radio Service" (ANSI C63.26-2015) and the guidance provided in KDB 842590 D01 v01r01 were used in the measurement of the EUT.

Conducted Average Output Power:

KDB 971168 D01 v03r01 - Section 5

KDB 662911 D01 v02r01 - Section E)1) In-Band Power Measurements

ANSI C63.26-2015 - Section 5.2.4.4.1

Equivalent Isotropically Radiated Power (Power Spectral Density):

KDB 971168 D01 v03r01 - Section 5

KDB 662911 D01 v02r01 - Section E)2) In-Band Power Spectral Density (PSD) Measurements

b) Measure and sum spectral maxima across the outputs

ANSI C63.26-2015 - Section 5.2.4.5

Band Edge Emissions at Antenna Terminal

KDB 971168 D01 v03r01 - Section 6

KDB 662911 D01 v02r01 - Section E)3) Out-of-Band and Spurious Emission Measurements

a) Absolute Emission Limits

iii) Measure and add 10 log(N_{ANT}) dB

ANSI C63.26-2015 - Section 5.7

Spurious and Harmonic Emissions at Antenna Terminal

KDB 971168 D01 v03r01 - Section 6

KDB 662911 D01 v02r01 – Section E)3) Out-of-Band and Spurious Emission Measurements

a) Absolute Emission Limits

iii) Measure and add 10 log(N_{ANT}) dB

ANSI C63.26-2015 - Section 5.7

Peak-to-Average Power Ratio:

KDB 971168 D01 v03r01 – Section 5.7 ANSI C63.26-2015 – Section 5.2.3.4

Occupied Bandwidth:

KDB 971168 D01 v03r01 – Section 4.2 ANSI C63.26-2015 – Section 5.4.3

Radiated unwanted emission

KDB 971168 D01 v03r01 – Section 7 ANSI C63.26-2015 – Section 5.8

Frequency stability

KDB 971168 D01 v03r01 – Section 9 ANSI C63.26-2015 – Section 5.6

3.2 Measurement Software

Test item	Name	Version
Conducted Measurement, Radiated Measurement	Node B automation	1.0

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4.0 MEASUREMENT UNCERTAINTY

The measurement uncertainties shown below were calculated in accordance with the requirements of ANSI C63.4-2014. All measurement uncertainty values are shown with a coverage factor of k=2 to indicate a 95% level of confidence. The measurement uncertainty shown below meets or exceeds the U_{CISPR} measurement uncertainty values specified in CISPR 16-4-2 and, thus, can be compared directly to specified limits to determine compliance.

Contribution	Expanded Uncertainty (±dB)
Conducted Bench Top Measurements	1.20
Radiated Disturbance (<1GHz)	3.01
Radiated Disturbance (>1GHz)	5.56
Radiated Disturbance (>18GHz)	3.16

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5.0 TEST EQUIPMENT CALIBRATION DATA

Test Equipment Calibration is traceable to the National Institute of Standards and Technology (NIST). Measurements antennas used during testing were calibrated in accordance to the requirements of ANSI C63.5-2017.

Manufacture	Model	Description	Cal Date	Cal interval	Cal Due	Serial Number
KEYSIGHT	N9030B	PXA Signal Analyzer	05/11/2021	Annual	05/10/2022	MY57142018
KEYSIGHT	N9020B	MXA Signal Analyzer	11/13/2020	Annual	11/12/2021	MY55470135
Rohde & Schwarz	FSW	Signal & Spectrum Analyzer	09/17/2020	Annual	09/16/2021	101250
KIKISUI	PWR1201ML	DC POWER SUPPLY	05/25/2021	Annual	05/24/2022	ZL000972
SUKSAN TECHNOLOGY	SE-CT-10	Temperature Chamber	09/17/2020	Annual	09/16/2021	191021
Rohde & Schwarz	TS-SFUNIT-Rx	Shielded Filter Unit	02/19/2021	Annual	02/18/2022	102131
Schwarzbeck	VULB9162	Broadband TRILOG Antenna	07/13/2021	Biennial	07/12/2023	9162-217
Sunol sciences	DRH-118	Horn Antenna	01/12/2021	Biennial	01/11/2023	A060215
Schwarzbeck	BBHA 9170	Horn Antenna	09/02/2020	Biennial	09/01/2022	1037
Reachline	250W18N-40FF	Attenuator	03/17/2021	Annual	03/16/2022	PK0291
Reachline	250W18N-40FF	Attenuator	03/17/2021	Annual	03/16/2022	PK0292
Reachline	250W18N-40FF	Attenuator	03/17/2021	Annual	03/16/2022	PK0294
Reachline	250W18N-40FF	Attenuator	03/17/2021	Annual	03/16/2022	PK0295
RF One	RFH1840NA250-D	Attenuator	07/07/2021	Annual	07/06/2022	PG0502
RF One	RFH1820NA250-D	Attenuator	07/07/2021	Annual	07/06/2022	PG0504
RF One	RFH1820NA250-D	Attenuator	07/07/2021	Annual	03/16/2022	PG0503
Weinschel	290-40-33	Attenuator	07/06/2021	Annual	07/05/2022	CL4563
Weinschel	290-40-33	Attenuator	07/06/2021	Annual	07/05/2022	CL4564

Table 5-1. Test Equipment

Notes:

- 1. For equipment listed above that has a calibration date or calibration due date that falls within the test date range, care was taken to ensure that this equipment was used after the calibration date and before the calibration due date.
- 2. Equipment with a calibration date of "N/A" shown in this list was not used to make direct calibrated measurements.

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6.0 SAMPLE CALCULATIONS

Emission Designator

QPSK Modulation

Emission Designator = 4M48G7D

Occupied Bandwidth = 4.48 MHz

G = Phase Modulation

7 = Quantized/Digital Info

D = Data transmission, telemetry, telecommand

QAM Modulation

Emission Designator = 4M47W7D

Occupied Bandwidth = 4.47 MHz

W = Amplitude/Angle Modulated

7 = Quantized/Digital Info

D = Data transmission, telemetry, telecommand

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TEST RESULTS

7.1 **Summary**

Company Name: SAMSUNG Electronics Co., Ltd.

FCC ID: A3LRF4437D-25D

FCC Classification: **PCS Licensed Transmitter**

Mode(s): **LTE**

FCC Part Section(s)	Test Description	Test Condition	Test Result	Reference
§ 2.1049	Occupied Bandwidth		PASS	Section 7.2
§ 2.1046	Conducted Average Output Power		PASS	Section 7.3
§ 2.1046, § 24.232, § 27.50(d)	Equivalent Isotropically Radiated Power (Power Spectral Density		PASS	Section 7.4
§ 2.1046, § 24.232, § 27.50(d)	Peak-to-average power ratio	CONDUCTED	PASS	Section 7.5
§ 2.1051, § 24.238, § 27.53(h)	Band Edge Emissions at Antenna Terminal		PASS	Section 7.6
§ 2.1051, § 24.238, § 27.53(h)	Spurious and Harmonic Emissions at Antenna Terminal		PASS	Section 7.7
§ 2.1055	Frequency stability		PASS	Section 7.9
§ 2.1051, § 24.238, § 27.53(h)	Radiated unwanted emission	RADIATED	PASS	Section 7.8

Table 7-1. Summary of Test Results

Notes:

- 1) All modes of operation and data rates were investigated. The test results shown in the following sections represent the worst case emissions.
- 2) The correction table was used to account for the losses of the cables and attenuators used to test the EUT at all frequencies of interest.
- The analyzer plots were all taken with a correction table loaded into the analyzer.
- 4) All antenna port conducted emissions testing was performed on a test bench with the antenna port of the EUT connected to the spectrum analyzer through calibrated cables and attenuators.
- 5) This unit was tested while powered by a 48V DC power source.

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7.2 Occupied Bandwidth

§ 2.1049

Test Overview

The occupied bandwidth, that is the frequency bandwidth such that, below its lower and above its upper frequency limits, the mean powers radiated are each equal to 0.5 percent of the total mean power radiated by a given emission shall be measured. All modes of operation were investigated and the worst case configuration results are reported in this section.

Test Procedures Used

KDB 971168 D01 v03r01 - Section 4.2, Section 4.3

ANSI C63.26-2015 - Section 5.4.3, Section 5.4.4

Test Setting

The measurement was made using a direct connection between the RF output of the EUT and the spectrum analyzer. The spectrum analyzer setting were as follows:

- The signal analyzer's automatic bandwidth measurement capability was used to perform the 99% occupied bandwidth and the 26dB bandwidth. The bandwidth measurement was not influenced by any intermediate power nulls in the fundamental emission.
- 2. RBW = 1 5% of the expected OBW
- 3. VBW ≥ 3 x RBW
- 4. Detector = Peak
- 5. Trace mode = max hold
- Sweep = auto couple
- 7. The trace was allowed to stabilize
- 8. If necessary, steps 2-7 were repeated after changing the RBW such that it would be within 1-5% of the 99% occupied bandwidth observed in Step 7

Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.

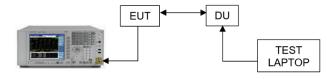


Figure 7-1. Test Instrument & Measurement Setup

Limit

The occupied bandwidth shall not exceed the equipment's channel bandwidth, which is declared by the manufacturer.

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Channel	Port	OBW (MHz)				
Channel	FUIL	QPSK	16QAM	64QAM	256QAM	
	0	4.47	4.47	4.48	4.47	
Low	1	4.47	4.47	4.48	4.48	
Low	2	4.47	4.47	4.48	4.48	
	3	4.47	4.47	4.48	4.47	
	0	4.48	4.47	4.48	4.48	
Middle	1	4.47	4.47	4.48	4.48	
ivildale	2	4.47	4.47	4.48	4.47	
	3	4.48	4.47	4.48	4.48	
	0	4.48	4.47	4.48	4.48	
High	1	4.47	4.47	4.48	4.48	
riigii	2	4.47	4.47	4.48	4.48	
	3	4.47	4.47	4.48	4.48	

Table 7-2. Occupied Bandwidth Summary Data (B2_5M_1C)

Channal	Dowt		OBW	(MHz)	
Channel	Port	QPSK	16QAM	64QAM	256QAM
	0	8.95	8.95	8.98	8.95
Low	1	8.95	8.96	8.97	8.95
LOW	2	8.96	8.96	8.95	8.95
	3	8.95	8.96	8.98	8.95
	0	8.95	8.96	8.98	8.96
Middle	1	8.96	8.95	8.96	8.95
Middle	2	8.95	8.97	8.97	8.95
	3	8.95	8.95	8.97	8.96
	0	8.96	8.94	8.98	8.94
Lliab	1	8.95	8.96	8.97	8.96
High	2	8.95	8.96	8.96	8.96
	3	8.97	8.96	8.96	8.96

Table 7-3. Occupied Bandwidth Summary Data (B2_10M_1C)

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Channel	Port	OBW (MHz)			
Chamilei	Poit	QPSK	16QAM	64QAM	256QAM
	0	13.41	13.41	13.40	13.40
Low	1	13.43	13.44	13.43	13.42
Low	2	13.42	13.43	13.43	13.43
	3	13.40	13.44	13.43	13.41
	0	13.41	13.43	13.44	13.40
Middle	1	13.41	13.42	13.44	13.41
ivildale	2	13.42	13.43	13.44	13.41
	3	13.42	13.44	13.42	13.39
	0	13.39	13.41	13.44	13.41
High	1	13.40	13.43	13.43	13.42
Flight	2	13.42	13.43	13.42	13.43
	3	13.43	13.44	13.41	13.42

Table 7-4. Occupied Bandwidth Summary Data (B2_15M_1C)

Channal	Dowt		OBW	(MHz)	
Channel	Port	QPSK	16QAM	64QAM	256QAM
	0	17.89	17.87	17.87	17.88
Low	1	17.86	17.89	17.88	17.87
Low	2	17.87	17.88	17.89	17.88
	3	17.88	17.86	17.89	17.88
	0	17.89	17.88	17.90	17.87
Middle	1	17.87	17.92	17.87	17.90
Middle	2	17.90	17.83	17.87	17.90
	3	17.87	17.85	17.87	17.85
	0	17.88	17.91	17.88	17.87
Lliab	1	17.90	17.90	17.90	17.87
High	2	17.88	17.89	17.88	17.91
	3	17.86	17.92	17.87	17.91

Table 7-5. Occupied Bandwidth Summary Data (B2_20M_1C)

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Plot 7-1. Occupied Bandwidth Plot (B2_5M_1C_QPSK - Low Channel, Port 0)



Plot 7-2. Occupied Bandwidth Plot (B2_5M_1C_16QAM - Low Channel, Port 0)



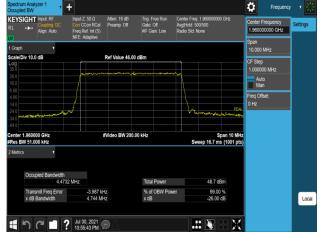
Plot 7-3. Occupied Bandwidth Plot (B2_5M_1C_64QAM - Low Channel, Port 0)



Plot 7-4. Occupied Bandwidth Plot (B2_5M_1C_256QAM - Low Channel, Port 1)



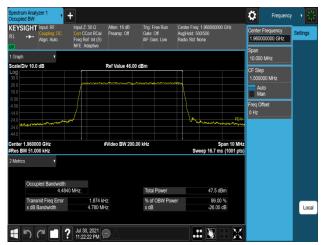
Plot 7-5. Occupied Bandwidth Plot (B2_5M_1C_QPSK - Mid Channel, Port 0)



Plot 7-6. Occupied Bandwidth Plot (B2_5M_1C_16QAM – Mid Channel, Port 0)

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Plot 7-7. Occupied Bandwidth Plot (B2_5M_1C_64QAM - Mid Channel, Port 0)



Plot 7-8. Occupied Bandwidth Plot (B2_5M_1C_256QAM – Mid Channel, Port 0)



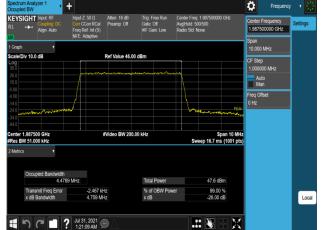
Plot 7-9. Occupied Bandwidth Plot (B2_5M_1C_QPSK - Low Channel, Port 2)



Plot 7-10. Occupied Bandwidth Plot (B2_5M_1C_16QAM - Low Channel, Port 2)



Plot 7-11. Occupied Bandwidth Plot (B2_5M_1C_64QAM - Low Channel, Port 2)



Plot 7-12. Occupied Bandwidth Plot (B2_5M_1C_256QAM - Low Channel, Port 2)

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Plot 7-13. Occupied Bandwidth Plot (B2_10M_1C_QPSK - Low Channel, Port 2)



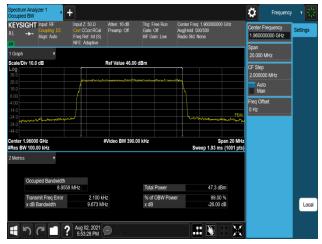
Plot 7-14. Occupied Bandwidth Plot (B2_10M_1C_16QAM - Low Channel, Port 1)



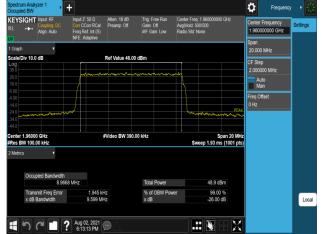
Plot 7-15. Occupied Bandwidth Plot (B2_10M_1C_64QAM - Low Channel, Port 0)



Plot 7-16. Occupied Bandwidth Plot (B2_10M_1C_256QAM - Low Channel, Port 0)



Plot 7-17. Occupied Bandwidth Plot (B2_10M_1C_QPSK - Mid Channel, Port 1)



Plot 7-18. Occupied Bandwidth Plot (B2_10M_1C_16QAM – Mid Channel, Port 2)

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Plot 7-19. Occupied Bandwidth Plot (B2_10M_1C_64QAM - Mid Channel, Port 0)



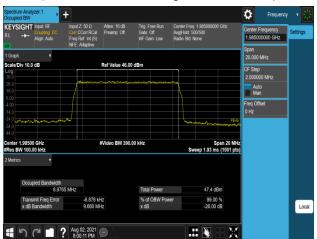
Plot 7-20. Occupied Bandwidth Plot (B2_10M_1C_256QAM – Mid Channel, Port 0)



Plot 7-21. Occupied Bandwidth Plot (B2_10M_1C_QPSK - High Channel, Port 3)



Plot 7-22. Occupied Bandwidth Plot (B2_10M_1C_16QAM – High Channel, Port 1)



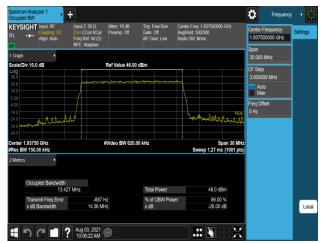
Plot 7-23. Occupied Bandwidth Plot (B2_10M_1C_64QAM - High Channel, Port 0)



Plot 7-24. Occupied Bandwidth Plot (B2_10M_1C_256QAM – High Channel, Port 1)

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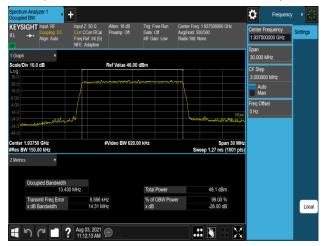
Plot 7-25. Occupied Bandwidth Plot (B2_15M_1C_QPSK - Low Channel, Port 1)



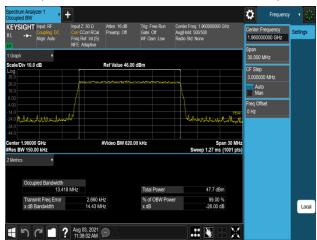
Plot 7-26. Occupied Bandwidth Plot (B2_15M_1C_16QAM - Low Channel, Port 1)



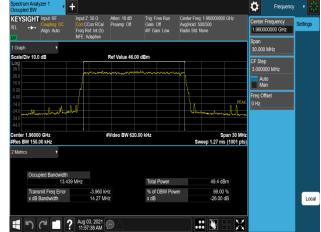
Plot 7-27. Occupied Bandwidth Plot (B2_15M_1C_64QAM - Low Channel, Port 1)



Plot 7-28. Occupied Bandwidth Plot (B2_15M_1C_256QAM - Low Channel, Port 2)



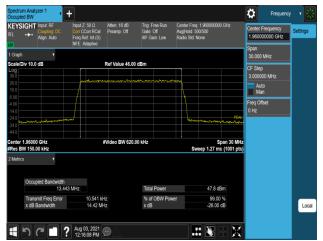
Plot 7-29. Occupied Bandwidth Plot (B2_15M_1C_QPSK - Mid Channel, Port 2)



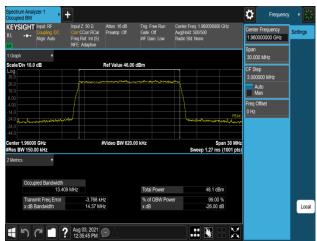
Plot 7-30. Occupied Bandwidth Plot (B2_15M_1C_16QAM – Mid Channel, Port 3)

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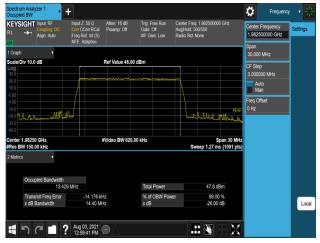




Plot 7-31. Occupied Bandwidth Plot (B2_15M_1C_64QAM - Mid Channel, Port 0)



Plot 7-32. Occupied Bandwidth Plot (B2_15M_1C_256QAM – Mid Channel, Port 1)



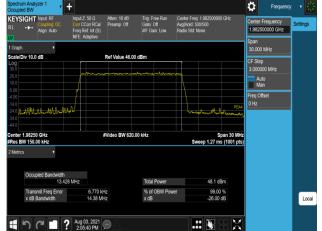
Plot 7-33. Occupied Bandwidth Plot (B2_15M_1C_QPSK - High Channel, Port 3)



Plot 7-34. Occupied Bandwidth Plot (B2_15M_1C_16QAM – High Channel, Port 3)



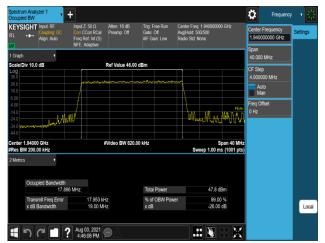
Plot 7-35. Occupied Bandwidth Plot (B2_15M_1C_64QAM - High Channel, Port 0)



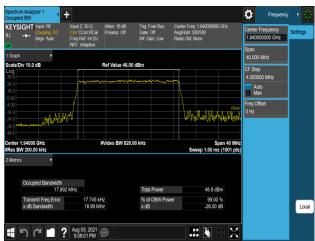
Plot 7-36. Occupied Bandwidth Plot (B2_15M_1C_256QAM – High Channel, Port 2)

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Plot 7-37. Occupied Bandwidth Plot (B2_20M_1C_QPSK - Low Channel, Port 0)



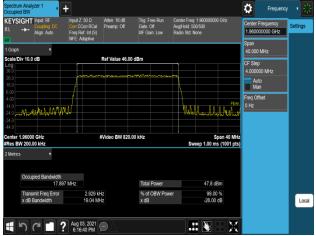
Plot 7-38. Occupied Bandwidth Plot (B2_20M_1C_16QAM - Low Channel, Port 1)



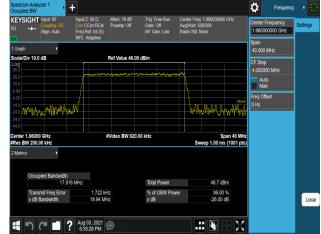
Plot 7-39. Occupied Bandwidth Plot (B2_20M_1C_64QAM - Low Channel, Port 2)



Plot 7-40. Occupied Bandwidth Plot (B2_20M_1C_256QAM - Low Channel, Port 0)



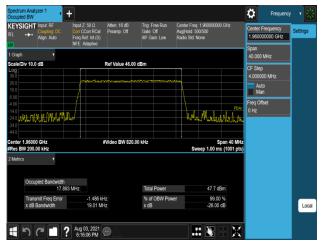
Plot 7-41. Occupied Bandwidth Plot (B2_20M_1C_QPSK - Mid Channel, Port 2)



Plot 7-42. Occupied Bandwidth Plot (B2_20M_1C_16QAM – Mid Channel, Port 1)

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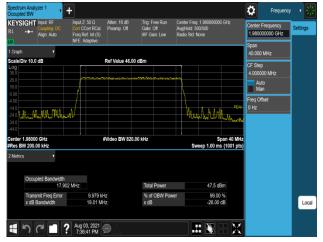




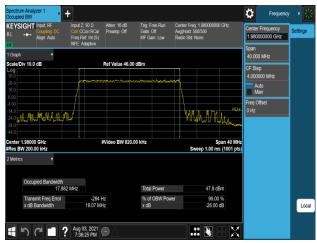
Plot 7-43. Occupied Bandwidth Plot (B2_20M_1C_64QAM - Mid Channel, Port 0)



Plot 7-44. Occupied Bandwidth Plot (B2_20M_1C_256QAM – Mid Channel, Port 1)



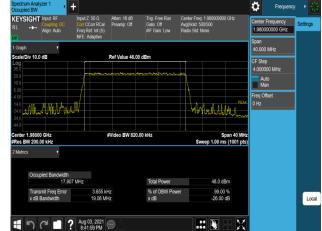
Plot 7-45. Occupied Bandwidth Plot (B2_20M_1C_QPSK - High Channel, Port 1)



Plot 7-46. Occupied Bandwidth Plot (B2_20M_1C_16QAM - High Channel, Port 0)



Plot 7-47. Occupied Bandwidth Plot (B2_20M_1C_64QAM - High Channel, Port 1)



Plot 7-48. Occupied Bandwidth Plot (B2_20M_1C_256QAM – High Channel, Port 2)

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Channel	Port	OBW (MHz)				
Channel	Poit	QPSK	16QAM	64QAM	256QAM	
	0	9.43	9.42	9.42	9.43	
Low	1	9.43	9.41	9.43	9.45	
Low	2	9.43	9.42	9.44	9.44	
	3	9.42	9.43	9.44	9.45	
	0	9.44	9.41	9.44	9.45	
Middle	1	9.43	9.42	9.45	9.45	
ivildale	2	9.42	9.43	9.42	9.43	
	3	9.43	9.41	9.43	9.44	
	0	9.42	9.42	9.44	9.45	
High	1	9.42	9.43	9.43	9.45	
High	2	9.43	9.43	9.42	9.42	
	3	9.43	9.42	9.44	9.44	

Table 7-6. Occupied Bandwidth Summary Data (B2_5M+5M_2C)

Channal	Dowt	OBW (MHz)			
Channel	Port	QPSK	16QAM	64QAM	256QAM
	0	23.67	23.69	23.65	23.70
Low	1	23.66	23.66	23.65	23.68
LOW	2	23.69	23.71	23.69	23.64
	3	23.63	23.69	23.67	23.67
	0	23.68	23.64	23.68	23.64
Middle	1	23.66	23.67	23.67	23.66
Middle	2	23.62	23.63	23.64	23.65
	3	23.64	23.65	23.66	23.69
	0	23.61	23.60	23.63	23.66
High	1	23.65	23.63	23.70	23.66
	2	23.69	23.65	23.67	23.66
	3	23.65	23.69	23.70	23.69

Table 7-7. Occupied Bandwidth Summary Data (B2_5M+20M_2C)

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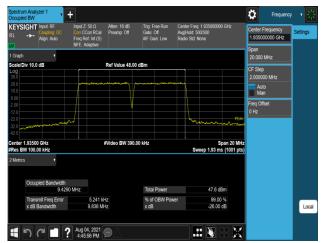


Channel	Port	OBW (MHz)				
Channel	Poil	QPSK	16QAM	64QAM	256QAM	
	0	28.30	28.34	28.27	28.25	
Low	1	28.28	28.30	28.28	28.27	
LOW	2	28.31	28.31	28.30	28.26	
	3	28.26	28.24	28.29	28.29	
	0	28.28	28.30	28.30	28.32	
Middle	1	28.33	28.28	28.28	28.26	
ivildale	2	28.26	28.26	28.31	28.29	
	3	28.26	28.33	28.28	28.32	
	0	28.28	28.21	28.30	28.27	
High	1	28.29	28.33	28.27	28.26	
	2	28.27	28.32	28.31	28.31	
	3	28.29	28.25	28.32	28.30	

Table 7-8. Occupied Bandwidth Summary Data (B2_10M+20M_2C)

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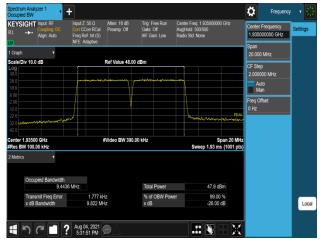




Plot 7-49. Occupied Bandwidth Plot (B2_5M+5M_2C_QPSK - Low Channel, Port 0)



Plot 7-50. Occupied Bandwidth Plot (B2_5M+5M_2C_16QAM - Low Channel, Port 3)



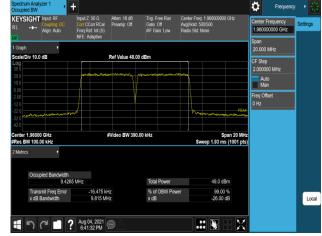
Plot 7-51. Occupied Bandwidth Plot (B2_5M+5M_2C_64QAM - Low Channel, Port 2)



Plot 7-52. Occupied Bandwidth Plot (B2_5M+5M_2C_256QAM - Low Channel, Port 1)



Plot 7-53. Occupied Bandwidth Plot (B2_5M+5M_2C_QPSK - Mid Channel, Port 0)



Plot 7-54. Occupied Bandwidth Plot (B2_5M+5M_2C_16QAM - Mid Channel, Port 2)

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